Skip to Main Content

IEEE.org | IEEE Xplore Digital Library | IEEE Standards Association | Spectrum Online | More IEEE Sites





Search Term(s)

Advanced Search | Preferences | Search Tips

Browse

- Journals & Magazines
- Conference Proceedings
- Standards
- Books
- Educational Courses
- · Technology Surveys
- · My Settings
 - o Alerts
 - o Purchase History
 - o Saved Searches
 - o Sign In
 - o What can I access?
- Cart

Terms of Use | Feedback Help

Search Results

You searched for: (((work or boot) near sector) near mounting) and ((record or store or cach) near (address near target near sector) near (data or content)) and ((completion or finish) near (backup or write or copy or replication or mirror) near (target or other or different or second\$4) near ((work or boot) near sector))





Email Selected
Results

Print

Results per Page 25 Showing 1 - 15 of 15 results Select All | Deselect All

X-ray excited optical luminescence detection by scanning near-field optical microscope: A new tool for nanoscience

Larcheri, Silvia; Rocca, Francesco; Jandard, Frank; Pailharey, Daniel; Graziola, Roberto; Kuzmin, Alexei; Purans, Juris;

Review of Scientific Instruments

Volume: 79, Issue: 1

Digital Object Identifier: 10.1063/1.2827485

Publication Year: 2008, Page(s): 013702 - 013702-9

AIP Journals

Abstract | Full Text: PDF (507 KB)

A real-time and color-based computer vision for traffic monitoring system

Mao-Chi Huang; Shwu-Huey Yen;

Multimedia and Expo, 2004. ICME '04. 2004 IEEE International Conference on

Volume: 3

Publication Year: 2004, Page(s): 2119 - 2122 Vol.3

IEEE Conferences

AbstractPlus | Full Text: PDF (639 KB)



Multifunctional catheters combining intracardiac ultrasound imaging and electrophysiology sensing

Stephens, D.N.; Cannata, J.; Ruibin Liu; Jian Zhong Zhao; Shung, K.K.; Hien Nguyen; Chia, R.; Dentinger, A.; Wildes, D.; Thomenius, K.E.; Mahajan, A.; Shivkumar, K.; Kang Kim; O'Donnell, M.;

Nikoozadeh, A.; Oralkan, O.; Khuri-Yakub, P.T.; Sahn, D.J.;

Ultrasonics, Ferroelectrics and Frequency Control, IEEE Transactions on

Volume: 55, Issue: 7

Digital Object Identifier: 10.1109/TUFFC.2008.834

Publication Year: 2008, Page(s): 1570 - 1581

IEEE Journals





Divergence measurement of light ion beams using ultracompact ion pinhole cameras on PBFA II (abstract)

Haill, T.; Johnson, D.; Bailey, J.; Leeper, R.; Hebron, D.; Stygar, W.;

Review of Scientific Instruments

Volume: 63, Issue: 10

Digital Object Identifier: 10.1063/1.1143561

Publication Year: 1992, Page(s): 4782 - 4782

AIP Journals

Abstract | Full Text: PDF (52 KB)

Shallow angle LIDAR for wave measurement

Horwood, J.M.K.; Thurley, R.W.F.; Belmont, M.R.; Baker, J.;

Oceans 2005 - Europe

Volume: 2

Publication Year: 2005, Page(s): 1151 - 1154 Vol. 2

IEEE Conferences

AbstractPlus | Full Text: PDF (170 KB)



Comparison of a few recording current meters in San Francisco Bay, California

Cheng, R.;

Current Measurement, Proceedings of the 1978 IEEE First Working Conference on

Volume: 1

Publication Year: 1978, Page(s): 293 - 301

IEEE Conferences

AbstractPlus | Full Text: PDF (528 KB)



Dependence on axial magnetic field of the radiation from a high power gas-filled backward wave oscillator

Minami, K.; Kobayashi, S.; Hayatsu, Y.; Sato, T.; Granatstein, V.L.;

Pulsed Power Plasma Science, 2001. IEEE Conference Record - Abstracts

Digital Object Identifier: 10.1109/PPPS.2001.960924

Publication Year: 2001

IEEE Conferences

AbstractPius | Full Text: PDF (35 KB)



Time-resolved perturbations near a self-biased, planar probe

Oksuz, L.; Goodyear, A.; Barroy, P.R.J.; Braithwaite, N.S.J.;

Plasma Science, 2002. ICOPS 2002. IEEE Conference Record - Abstracts. The 29th IEEE International Conference on

Digital Object Identifier: 10.1109/PLASMA.2002.1030568

Publication Year: 2002

IEEE Conferences

AbstractPlus | Full Text: PDF (197 KB)



Numerical Simulation of Metal Plasma Immersion Ion Implantation and Deposition (MEPIIID) on a Sharp Cone and a Fine Tip

Kwok, D.T.K.; Cornet, C.;

Plasma Science, 2005. ICOPS '05. IEEE Conference Record - Abstracts. IEEE International Conference on

Digital Object Identifier: 10.1109/PLASMA.2005.359280

Publication Year: 2005, Page(s): 226 - 226

IEEE Conferences

AbstractPlus | Full Text: PDF (1098 KB)



ADCP estimates of Reynolds and bottom stress

Howarth, M.J.:

Current Measurement Technology, 2003. Proceedings of the IEEE/OES Seventh Working Conference on

Digital Object Identifier: 10.1109/CCM.2003.1194316

Publication Year: 2003, Page(s): 219 - 224

IEEE Conferences

AbstractPlus | Full Text: PDF (451 KB)



A fieldable-prototype, large-area, gamma-ray imager for orphan source search

Ziock, K.P.; Fabris, L.; Carr, D.; Collins, J.; Cunningham, M.; Habte, F.; Karnowski, T.; Marchant, W.;

Nuclear Science Symposium Conference Record, 2007. NSS '07. IEEE

Volume: 2

Digital Object Identifier: 10.1109/NSSMIC.2007.4437175

Publication Year: 2007, Page(s): 949 - 958

IEEE Conferences

AbstractPlus | Full Text: PDF (681 KB)



Near-surface current meter array measurements of internal gravity waves

Mantrom, D.D.; Jones, H.E.; Chambers, D.H.;

Current Measurement, 1995., Proceedings of the IEEE Fifth Working Conference on

Digital Object Identifier: 10.1109/CCM.1995.516163

Publication Year: 1995, Page(s): 131 - 136

IEEE Conferences

AbstractPlus | Full Text: PDF (1068 KB)



Diamond Start Detectors

	Digital Object Identifier: 10.1109/NSSMIC.2009.5401672
J	Publication Year: 2009, Page(s): 407 - 411
]	IEEE Conferences
•	AbstractPlus Full Text: PDF (388 KB)
Sec. of	Currick 3 Advanced
-	Wireless waves
(Cole, R.; Weisberg, R.; Trenaman, N.; Amundsen, K.; Current Measurement Technology, 2005. Proceedings of the IEEE/OES Fighth Working Conference on Digital Object Identifier: 10.1109/CCM.2005.1506354 Publication Year: 2005, Page(s): 119 - 121
]	IEEE Conferences
	AbstractPfus Full Text: PDF (341 KB)
or news	Country 8 Country 8
	Aanderaa DCM 12 Doppler current meter performance characteristics
(Appell, G.F.; Chapin, J.L.; Bowers, G.W.; Current Measurement, 1995., Proceedings of the IEEE Fifth Working Conference on Digital Object Identifier: 10.1109/CCM.1995.516148 Publication Year: 1995, Page(s): 43 - 46
]	IEEE Conferences
,	AbstractPlus Full Text: PDF (332 KB)
Acres 1	Carlot 8
1	e/Expand Results

IEEE Xplore - SearchResult

☐ Thomenius, K.E. (1)

EE Xplore - SearchResult		
☐ Imaging & Detection Program, Lawrence Livermore Nat. Lab., CA (1)		
GSI Helmholtzzentrum, Darmstadt, Germany (1)		
Publication Title		
□ Current Measurement, 1995., Proceedings of the IEEE Fifth Working Conference on (2) □ Review of Scientific Instruments (2) □ Ultrasonics, Ferroelectrics and Frequency Control, IEEE Transactions on (1) □ Pulsed Power Plasma Science, 2001. IEEE Conference Record - Abstracts (1) □ Plasma Science, 2002. ICOPS 2002. IEEE Conference Record - Abstracts. The 29th IEEE International Conference on (1) □ Current Measurement, Proceedings of the 1978 IEEE First Working Conference on (1) □ Current Measurement Technology, 2003. Proceedings of the IEEE/OES Seventh Working Conference on (1) □ Multimedia and Expo, 2004. ICME '04. 2004 IEEE International Conference on (1) □ Oceans 2005 - Europe (1) □ Current Measurement Technology, 2005. Proceedings of the IEEE/OES Eighth Working Conference on (1) □ Plasma Science, 2005. ICOPS '05. IEEE Conference Record - Abstracts. IEEE International Conference on (1) □ Nuclear Science Symposium Conference Record, 2007. NSS '07. IEEE (1)		
■ Nuclear Science Symposium Conference Record (NSS/MIC), 2009 IEEE (1)		
Publisher		
■ IEEE (13)		

http://iceexaplore-icee.org/search/searchresult.jsp?newsearch=true-dequeryText=...or+second%244.RB.+near+LB.LB.work+cc+boot.RB.+near+sector.RB.RB.&x=31.6xy=19 (9 of 11)7/9/2010 547:58 PM

☐ AIP (2)

☐ Components, Circuits, Devices & Systems (11)

Subject

Brought to you by

United States Patent and Trademark Office

- · Your institute subscribes to:
- IEEE/IET Electronic Library (IEL), IEEE Draft Standards Online Subscription
- · What can I access?

Terms of Use

SEARCHES FOR THIS SESSION

- (((work or boot) near sector) near mounting) and ((record or store or cach) near (address near target near sector) near (data or content)) and ((completion or finish) near (backup or write or copy or replication or mirror) near (target or other or different or secondS4) near ((work or boot) near sector)) (15)
- · More Search History

Additional Results

Application Notes (beta)



Help | Contact Us | Privacy & Security | Site Map | IEEE.org | Nondiscrimination Policy | Terms of Use

© Copyright 2010 IEEE - All Rights Reserved

Back to Top